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Application/Control No.	Applicant(s)/Patent under Reexamination	ent under	
10/619,468	CHIEN, HUI-CHUEH		
Examiner	Art Unit		
Rvan Lepisto	2883		

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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
See EAST search history	6/13/2005	RAL	
See PALM inventorship search			
See IEEEXplorer, INSPEC, IP.com and SPIE non-patent literature searches			
Consulted Brian Healy concerning allowable subject matter	1/27/2005	•	
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